

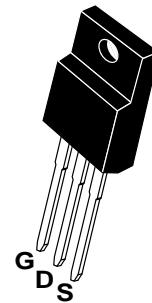


700V N-Channel MOSFET

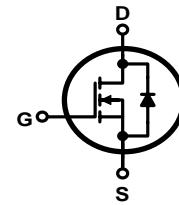
PIN Connection TO-220F

Features:

- Low Intrinsic Capacitances.
- Excellent Switching Characteristics.
- Extended Safe Operating Area.
- Unrivalled Gate Charge : $Q_g=30nC$ (Typ.).
- $BVDSS=700V, I_D=6A$
- $R_{DS(on)} : 2.3\Omega$ (Max) @ $V_G=10V$
- 100% Avalanche Tested



Schematic diagram



Marking Diagram



- Y = Year
 A = Assembly Location
 WW = Work Week
 FIR6N70F = Specific Device Code

Absolute Maximum Ratings ($T_a=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	700	V
I_D	Drain Current	$T_j=25^\circ C$	A
		$T_j=100^\circ C$	
$V_{GS(TH)}$	Gate Threshold Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note1)	300	mJ
I_{AR}	Avalanche Current (note2)	6	A
P_D	Power Dissipation ($T_j=25^\circ C$)	40	W
T_j	Junction Temperature(Max)	150	$^\circ C$
T_{stg}	Storage Temperature	-55~+150	$^\circ C$
T_L	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	$^\circ C$

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case	-	3.2	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance,Junction to Ambient	-	120	$^\circ C/W$



Electrical Characteristics (Ta=25°C unless otherwise noted)

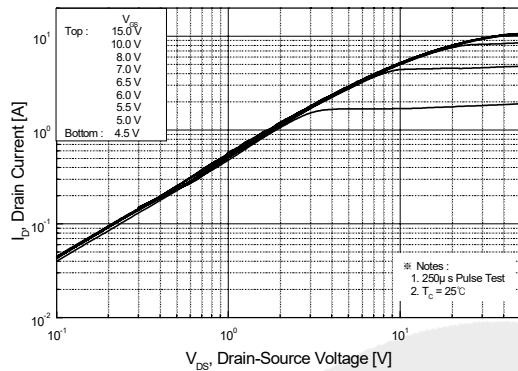
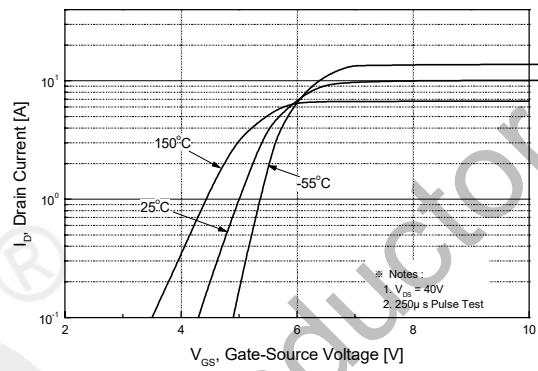
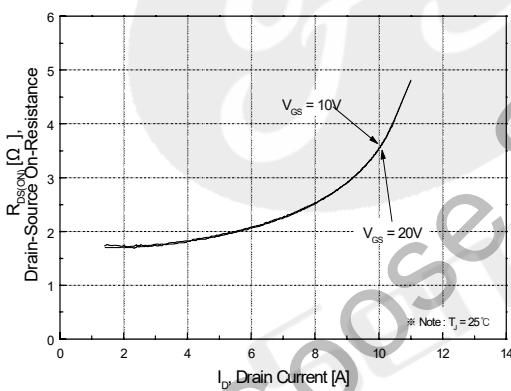
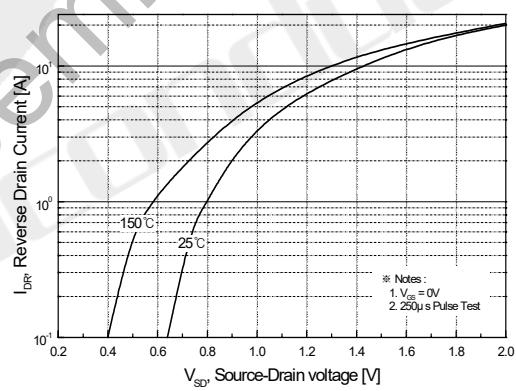
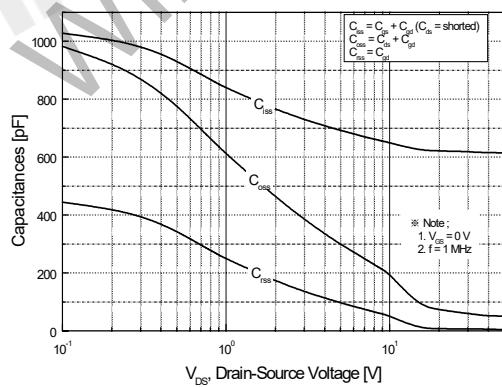
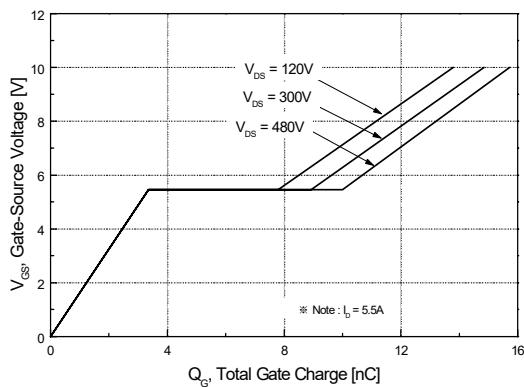
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0	700	-	-	V
△BV _{DSS} /△T _J	Breakdown Voltage Temperature Coefficient	I _D =250μA, Reference to 25°C	-	0.6	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =700V, V _{GS} =0V	-	-	1	μA
		V _{DS} =560V, T _j =125°C			10	
I _{GSSF}	Gate-body leakage Current, Forward	V _{GS} =+30V, V _{DS} =0V	-	-	100	nA
I _{GSSR}	Gate-body leakage Current, Reverse	V _{GS} =-30V, V _{DS} =0V	-	-	-100	
On Characteristics						
V _{GS(TH)}	Date Threshold Voltage	I _D =250μA, V _{DS} =V _{GS}	2	-	4	V
R _{DS(ON)}	Static Drain-Source On-Resistance	I _D =2.5A, V _{GS} =10V	-	-	2.3	Ω
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0, f=1.0MHz	-	1100	1400	pF
C _{oss}	Output Capacitance		-	125	150	
C _{rss}	Reverse Transfer Capacitance		-	15	120	
Switching Characteristics						
T _{d(on)}	Turn-On Delay Time	V _{DD} =350V, I _D =6A R _G =25Ω (Note 3,4)	-	13	35	ns
T _r	Turn-On Rise Time		-	45	100	
T _{d(off)}	Turn-Off Delay Time		-	25	60	
T _f	Turn-Off Rise Time		-	35	80	
Q _g	Total Gate Charge	V _{DS} =560V, V _{GS} =10V, I _D =6A (Note 3,4)	-	30	40	nC
Q _{gs}	Gate-Source Charge		-	3.5	-	
Q _{gd}	Gate-Drain Charge		-	6.5	-	
Drain-Source Diode Characteristics and Maximum Ratings						
I _s	Max. Diode Forward Current	-	-	-	6	A
I _{SM}	Max. Pulsed Forward Current	-	-	-	24	
V _{SD}	Diode Forward Voltage	I _D =6A	-	-	1.25	V
T _{rr}	Reverse Recovery Time	I _s =6A, V _{GS} =0V diF/dt=100A/μs (Note3)	-	310	-	nS
Q _{rr}	Reverse Recovery Charge		-	2.1	-	μC

Notes : 1, L=27.5mH, IAS=6A, VDD=50V, RG=25Ω, Starting TJ =25°C

2, Repetitive Rating : Pulse width limited by maximum junction temperature

3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%

4, Essentially Independent of Operating Temperature

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics

Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

Figure 5. Capacitance Characteristics

Figure 6. Gate Charge Characteristics


Typical Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

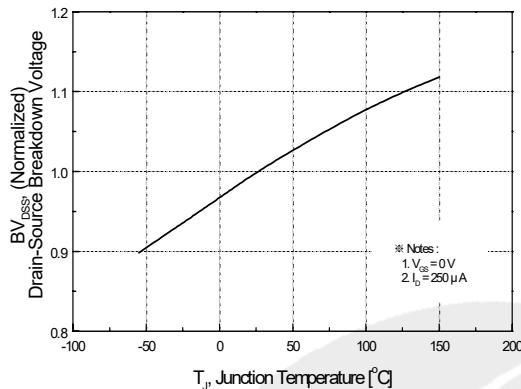


Figure 8. On-Resistance Variation vs. Temperature

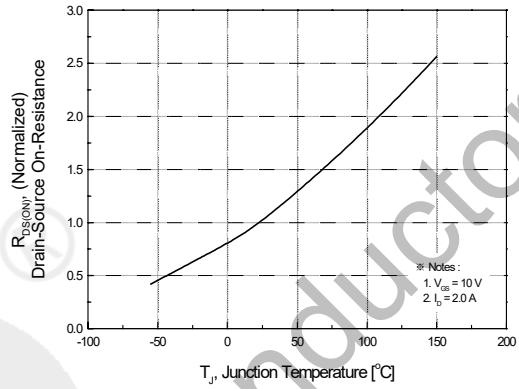


Figure 9. Maximum Safe Operating Area

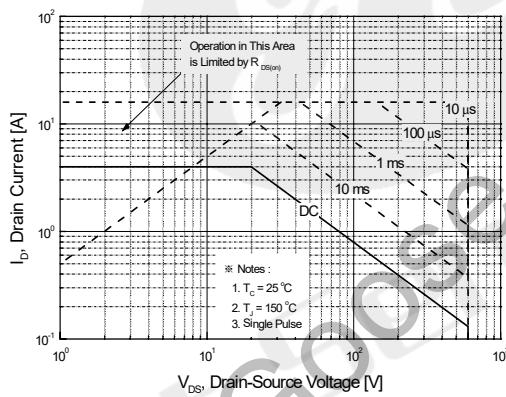
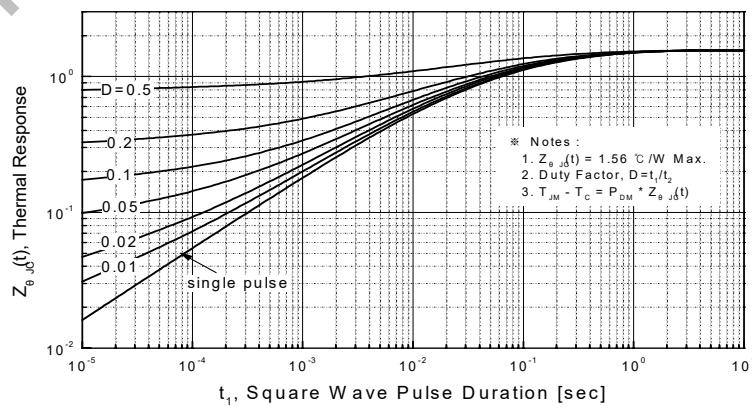
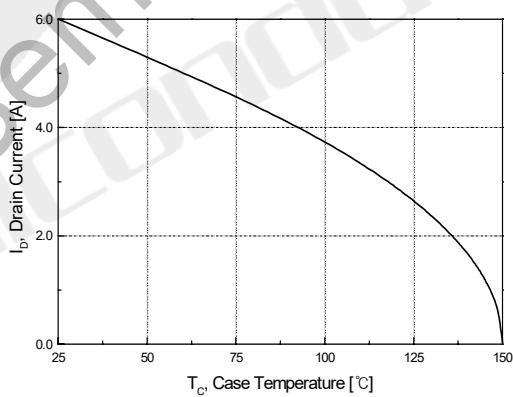
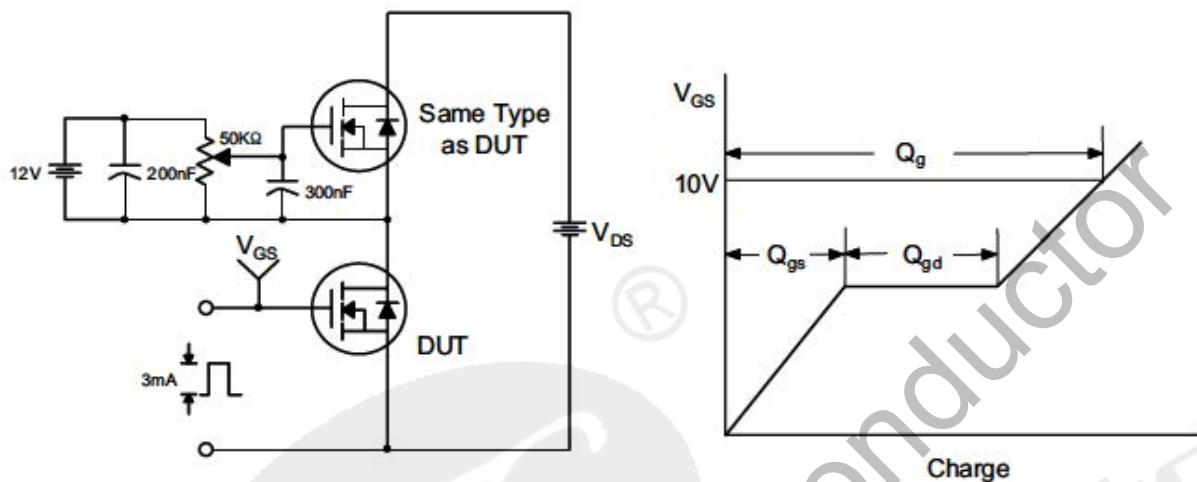


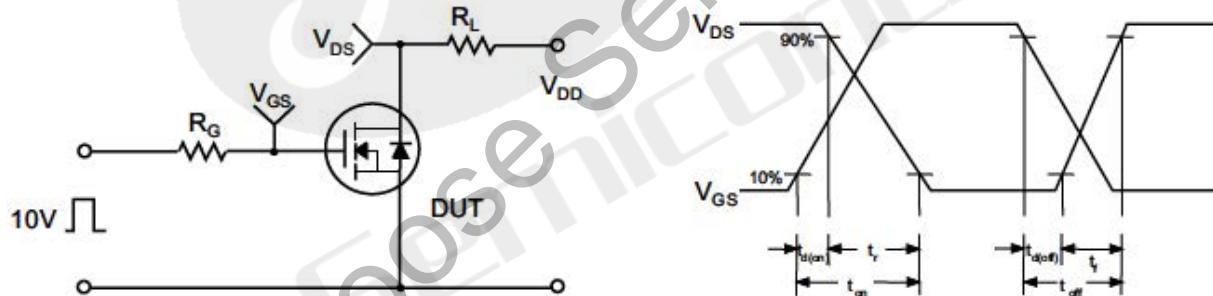
Figure 10. Maximum Drain Current vs. Case Temperature



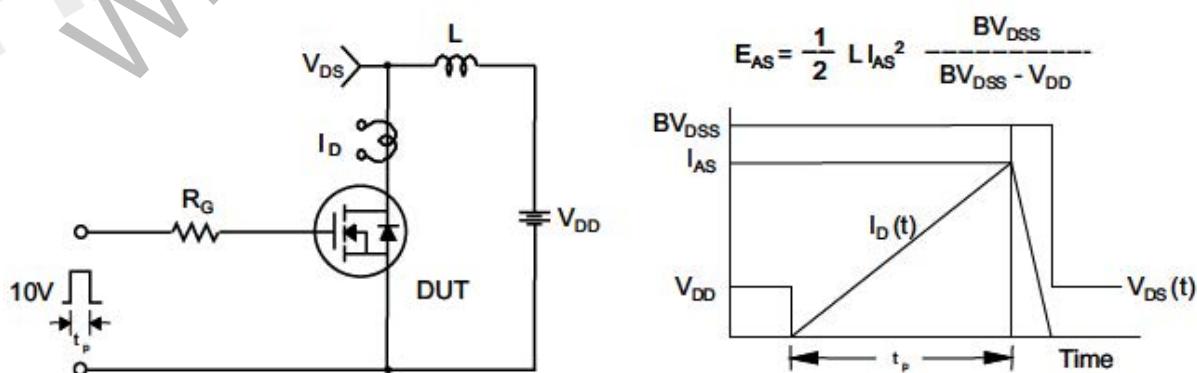
Gate Charge Test Circuit & Waveform



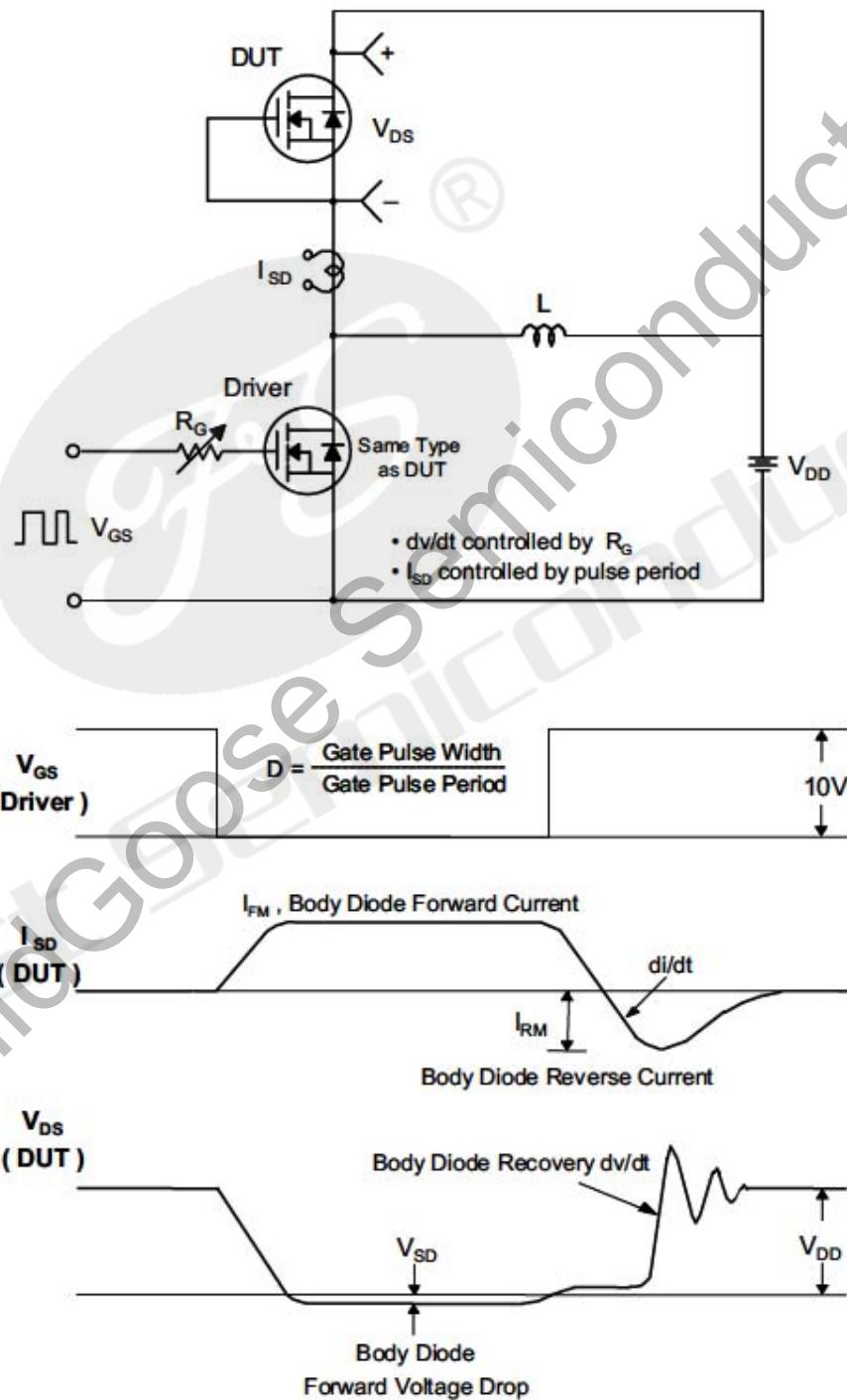
Resistive Switching Test Circuit & Waveforms



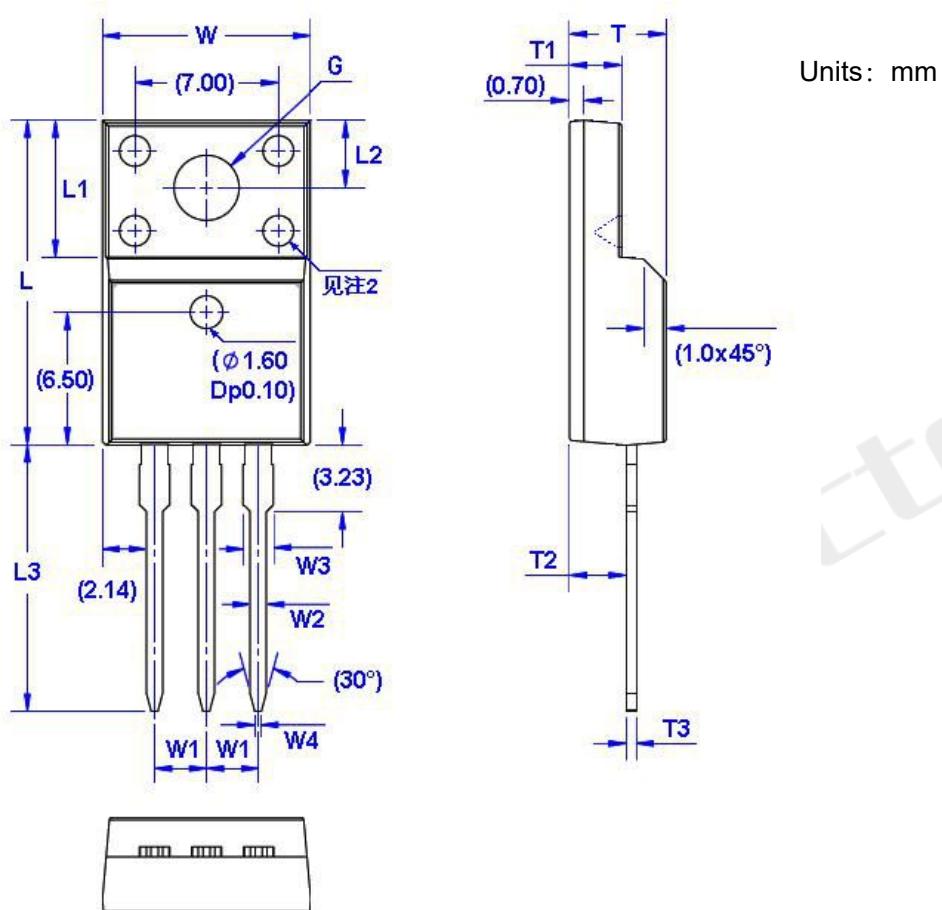
Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimension



Symbol	Size		Symbol	Size		Symbol	Size		Symbol	Size	
	Min	Max		Min	Max		Min	Max		Min	Max
W	9.96	10.36	W4	0.25	0.45	L3	12.78	13.18	T3	0.45	0.60
W1	2.54 (TYP)		L	15.67	16.07	T	4.50	4.90	G(Φ)	3.08	3.28
W2	0.70	0.90	L1	6.48	6.88	T1	2.34	2.74			
W3	1.24	1.47	L2	3.20	3.40	T2	2.56	2.96			



Declaration

- FIRST reserves the right to change the specifications, the same specifications of products due to different packaging line mold, the size of the appearance will be slightly different, shipped in kind, without notice! Customers should obtain the latest version information before ordering, and verify whether the relevant information is complete and up-to-date.
- Any semiconductor product under certain conditions has the possibility of failure or failure, The buyer has the responsibility to comply with safety standards and take safety measures when using FIRST products for system design and manufacturing, To avoid potential failure risks, which may cause personal injury or property damage!
- Product promotion endless, our company will wholeheartedly provide customers with better products!

ATTACHMENT

Revision History

Date	REV	Description	Page
2018.01.01	1.0	Initial release	